

<b>Notice of References Cited</b>	Application/Control No. 10/017,254	Applicant(s)/Patent Under Reexamination NAKANISHI ET AL.	
	Examiner John B Strege	Art Unit 2625	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-3,773,422	11-1973	Stavis et al.	356/630
	C	US-			
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	M	US-			

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	N	JP 11073948 A	03-1999	Japan	ARAI et al.	H01M 04/04
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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